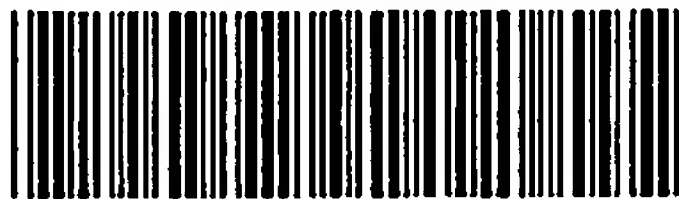


Search Notes

Application/Control No.

10/710,934

Examiner

David Mis

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
331	1A, 10, 11,	12/7/2005	DM
	16, 18,		
	25		
327	156-159		
332	127		
360	51		
375	376		
455	260		
UPDATED 3/14/06 <i>DM</i>			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
US66005	(see history)	3/14/06	<i>DM</i>

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR